Machine Learning: Advances in Models and Applications

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Message from the Guest Editor

The application area of machine learning is very broad, including engineering, industry, business, finance, medicine, and many other domains. ML covers a wide range of learning algorithms including the classical ones such as linear regression, k-nearest neighbors or decision trees, through support vector machines and neural networks, to newly developed algorithms such as deep learning and boosted tree models.

This Special Issue focuses on ML models and their applications in a diverse range of fields and problems. Papers are expected reporting substantive results on a wide range of learning methods, discussing conceptualization of a problem, data representation, feature engineering, ML models, critical comparisons with existing techniques and interpretation of results. Specific attention will be given to recently developed ML methods such as deep learning and boosted tree models.

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SpecialIssue

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Message from the Editor-in-Chief

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